Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/748,906	LEE ET AL.	
Examiner	Art Unit	
Sanih I Siddinui	2117	

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Class	Subclass	Date	Examiner	
714	720	11/16/2006	SS	
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Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East txt Search (SDR and DDR and DQ)	11/16/2006	SS
Double Patenting Inventors name search in palm	11/16/2006	SS
PLUS search	11/17/2006	SS
Updated east Txt Search	7/3/2007	SS